Power Field Effect Transistor N–Channel Enhancement Mode Silicon Gate TMOS

This TMOS Power FET is designed for high voltage, high speed power switching applications such as switching regulators, converters, solenoid and relay drivers.

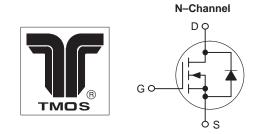
- Silicon Gate for Fast Switching Speeds
- Low R_{DS(on)} to Minimize On–Losses, Specified at Elevated Temperature
- Rugged SOA is Power Dissipation Limited
- Source-to-Drain Diode Characterized for Use with Inductive Loads

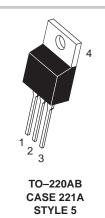


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TMOS POWER FET 4.5 AMPERES 500 VOLTS R_{DS(on)} = 1.5 Ω





PIN ASSIGNMENT			
1	Gate		
2	Drain		
3	Source		
4	Drain		

ORDERING INFORMATION

Device	Package	Shipping	
IRF830	TO-220AB	50 Units/Rail	

See the MTM4N45 Data Sheet for a complete set of design curves for the product on this data sheet. Design curves of the MTP4N45 are applicable for this product.

MAXIMUM RATINGS				
Rating	Symbol	Value	Unit	
Drain–Source Voltage	V _{DSS}	500	Vdc	
Drain–Gate Voltage ($R_{GS} = 1.0 M\Omega$)	V _{DGR}	500	Vdc	
Gate-Source Voltage	V _{GS}	±20	Vdc	
Drain Current Continuous, $T_C = 25^{\circ}C$ $T_C = 100^{\circ}C$ Peak, $T_C = 25^{\circ}C$	ID	4.5 3.0 18	Adc	
Total Power Dissipation @ T _C = 25°C Derate above 25°C	PD	75 0.6	Watts W/°C	
Operating and Storage Temperature Range	T _J , T _{stg}	-55 to 150	°C	

THERMAL CHARACTERISTICS

Thermal Resistance — Junction–to–Case — Junction–to–Ambient	R _{θJC} R _{θJA}	1.67 62.5	°C/W
Maximum Lead Temperature for Soldering Purposes, 1/8" from Case for 5 Seconds	ΤL	300	°C

IRF830

ELECTRICAL CHARACTERISTICS (T_C = 25°C unless otherwise noted)

Charae	Symbol	Min	Max	Unit		
OFF CHARACTERISTICS						
Drain-to-Source Breakdown Voltage $(V_{GS} = 0 \text{ Vdc}, I_D = 0.25 \text{ mAdc})$	V _{(BR)DSS}	500	_	Vdc		
Zero Gate Voltage Drain Current (V_{DS} = Rated V_{DSS} , V_{GS} = 0 Vdc) (V_{DS} = 0.8 Rated V_{DSS} , V_{GS} = 0 Vdc, T	I _{DSS}		0.2 1.0	mAdc		
Gate–Body Leakage Current, Forward $(V_{GSF} = 20 \text{ Vdc}, V_{DS} = 0)$	I _{GSS(f)}	_	100	nAdc		
$ \begin{array}{l} \mbox{Gate-Body Leakage Current, Reverse} \\ \mbox{(V}_{\mbox{GSR}} = 20 \mbox{ Vdc}, \mbox{ V}_{\mbox{DS}} = 0) \end{array} $		I _{GSS(r)}	_	100	nAdc	
ON CHARACTERISTICS ⁽¹⁾					1	
Gate Threshold Voltage $(V_{DS} = V_{GS}, I_D = 0.25 \text{ mA})$		V _{GS(th)}	2.0	4.0	Vdc	
Static Drain–to–Source On–Resistance $(V_{GS} = 10 \text{ Vdc}, I_D = 2.5 \text{ Adc})$	R _{DS(on)}	_	1.5	Ohm		
On–State Drain Current (V _{GS} = 10 V) (V _{DS} \geq 6.75 Vdc)	I _{D(on)}	4.5	_	Adc		
Forward Transconductance (V_{DS} ≥ 6.75 Vdc, I_D = 2.5 Adc)	9 _{FS}	2.5		mhos		
DYNAMIC CHARACTERISTICS		•				
Input Capacitance		C _{iss}	—	800	pF	
Output Capacitance	$(V_{DS} = 25 \text{ Vdc}, V_{GS} = 0 \text{ Vdc}, f = 1.0 \text{ MHz})$	C _{oss}	-	200		
Reverse Transfer Capacitance		C _{rss}	-	60		
SWITCHING CHARACTERISTICS (1)	•					
Turn–On Delay Time		t _{d(on)}	—	30	ns	
Rise Time	(V _{DD} = 200 Vdc, I _D = 2.5 Apk,	tr	-	30		
Turn–Off Delay Time	R _G = 15 Ω)	t _{d(off)}	—	55	1	
Fall Time		t _f	—	30	1	
Total Gate Charge		Qg	22 (Typ)	30	nC	
Gate-Source Charge	$(V_{DS} = 0.8 \text{ Rated } V_{DSS},$ $V_{GS} = 10 \text{ Vdc}, I_D = \text{Rated } I_D)$	Q _{gs}	12 (Typ)	_	1	
Gate–Drain Charge		Q _{gd}	10 (Typ)	_	1	
OURCE-DRAIN DIODE CHARACTERIS	rics ⁽¹⁾					
Forward On–Voltage		V _{SD}	1.1 (Typ)	1.6	Vdc	
Forward Turn–On Time	$(I_S = Rated I_D, V_{GS} = 0)$	t _{on}	Limited b	y stray ind	ductance	
Reverse Recovery Time			450 (Typ)	_	ns	
NTERNAL PACKAGE INDUCTANCE						
Internal Drain Inductance (Measured from the contact screw on tab to center of die) (Measured from the drain lead 0.25" from package to center of die)		L _D	3.5 (Typ) 4.5 (Typ)		nH	
Internal Source Inductance (Measured from the source lead 0.25" fr	L _S	7.5 (Typ)	_]		

(1) Pulse Test: Pulse Width \leq 300 µs, Duty Cycle \leq 2%.

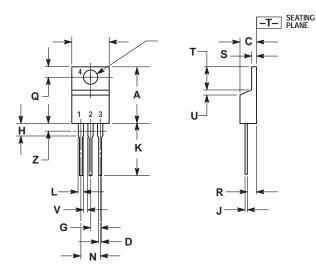
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PACKAGE DIMENSIONS

TO-220AB

CASE 221A-09

ISSUE Z



NOTES: 1. DIMENSIONING AND TOLERANCING PER ANSI Y14.5M, 1982. 2. CONTROLLING DIMENSION: INCH. 3. DIMENSION Z DEFINES A ZONE WHERE ALL BODY AND LEAD IRREGULARITIES ARE ALLOWED.

	INCHES		MILLIMETERS	
DIM	MIN	MAX	MIN	MAX
Α	0.570	0.620	14.48	15.75
В	0.380	0.405	9.66	10.28
С	0.160	0.190	4.07	4.82
D	0.025	0.035	0.64	0.88
F	0.142	0.147	3.61	3.73
G	0.095	0.105	2.42	2.66
Н	0.110	0.155	2.80	3.93
J	0.018	0.025	0.46	0.64
К	0.500	0.562	12.70	14.27
L	0.045	0.060	1.15	1.52
N	0.190	0.210	4.83	5.33
Q	0.100	0.120	2.54	3.04
R	0.080	0.110	2.04	2.79
S	0.045	0.055	1.15	1.39
Т	0.235	0.255	5.97	6.47
U	0.000	0.050	0.00	1.27
V	0.045		1.15	
Z		0.080		2.04

STYLE 5: PIN 1. GATE 2. DRAIN 3. SOURCE 4. DRAIN

IRF830

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